RELIABILITY REPORT

FOR

MAX412xxxA

PLASTIC ENCAPSULATED DEVICES

January 19, 2002

MAXIM INTEGRATED PRODUCTS

120 SAN GABRIEL DR.

SUNNYVALE, CA 94086

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Conclusion

The MAX412 successfully meets the quality and reliability standards required of all Maxim products. In addition, Maxim's continuous reliability monitoring program ensures that all outgoing product will continue to meet Maxim's quality and reliability standards.

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I. Device Description

A. General

The MAX412 dual op amp sets a new standard for noise performance in high-speed, low-voltage systems. A unique design not only combines low noise with +/-5V operation, but also consumes 25ma supply current per amplifier. Low voltage operation is guaranteed with an output voltage swing of $7.3V_{p-p}$ into 2K Ohm from +/-5V supplies. The MAX412 also operates from supply voltages between +/-2.4V and +/-5V fro greater Supply Flexibility.

Unity-gain stability, 28MHz bandwidth and 4.5V/uS slew rate ensure low-noise performance in a wide variety of wideband and measurement applications.

B. Absolute Maximum Ratings

Item	Rating
Supply Voltage (V+ to V-)	12V
Differential Input Currrent (Note 1)	+/-20mA
Storage Temp.	-65°C to +150°C
Lead Temp. (10 sec.)	+300°C
Power Dissipation	
8-Pin SO	471mW
8-Pin PDIP	727mW
Derates above +70°C	
8-Pin SO	5.88mW/°C
8-Pin PDIP	9/09mW/°C

II. Manufacturing Information

A. Description/Function:	Dual, 28MHz, Low-Noise, Low-Voltage, Precision Op Amp
B. Process:	CBP (Complimentary Bipolar Process)
C. Number of Device Transistors:	262
D. Fabrication Location:	Minnesota, USA
E. Assembly Location:	Philippines, Malaysia, Korea or Thailand
F. Date of Initial Production:	August, 1992

III. Packaging Information

A. Package Type:	8-Lead SO	8-Lead PDIP
B. Lead Frame:	Copper	Copper
C. Lead Finish:	Solder Plate	Solder Plate
D. Die Attach:	Silver-filled Epoxy	Silver-filled Epoxy
E. Bondwire:	Gold (1.0 mil dia.)	Gold (1.3 mil dia.)
F. Mold Material:	Epoxy with silica filler	Epoxy with silica filler
G. Assembly Diagram:	Buildsheet # 05-0601-0325	Buildsheet # 05-0601-0324
H. Flammability Rating:	Class UL94-V0	Class UL94-V0
I. Classification of Moisture Sensitivity per JEDEC standard JESD22-A112:	Level 1	Level 1

IV. Die Information

A. Dimensions:	80 x 72 mils
B. Passivation:	SiN/SiO (nitride/oxide)
C. Interconnect:	Aluminum/Si (Si = 1%)
D. Backside Metallization:	None
E. Minimum Metal Width:	Metal1: 6; Metal2: 8 microns (as drawn)
F. Minimum Metal Spacing:	Metal1: 2; Metal2: 3 microns (as drawn)
G. Bondpad Dimensions:	5 mil. Sq.
H. Isolation Dielectric:	SiO_2
I. Die Separation Method:	Wafer Saw

V. Quality Assurance Information

A. Quality Assurance Contacts: Jim Pedicord (Reliability Lab Manager)
Bryan Preeshl (Executive Director of QA)
Kenneth Huening (Vice President)

B. Outgoing Inspection Level: 0.1% for all electrical parameters guaranteed by the Datasheet.
0.1% For all Visual Defects.

C. Observed Outgoing Defect Rate: < 50 ppm

D. Sampling Plan: Mil-Std-105D

VI. Reliability Evaluation

A. Accelerated Life Test

The results of the 135°C biased (static) life test are shown in **Table 1**. Using these results, the Failure Rate (λ) is calculated as follows:

$$\lambda = \frac{1}{MTTF} = \frac{1.83}{192 \times 4389 \times 80 \times 2}$$

1.83: (Chi square value for MTTF upper limit)

192 x 4389 x 80 x 2: Temperature Acceleration factor assuming an activation energy of 0.8eV

$\lambda = 13.57 \times 10^{-9}$

λ = 13.57 F.I.T. (60% confidence level @ 25°C)

This low failure rate represents data collected from Maxim's reliability monitor program. In addition to routine production Burn-In, Maxim pulls a sample from every fabrication process three times per week and subjects it to an extended Burn-In prior to shipment to ensure its reliability. The reliability control level for each lot to be shipped as standard product is 59 F.I.T. at a 60% confidence level, which equates to 3 failures in an 80 piece sample. Maxim performs failure analysis on any lot that exceeds this reliability control level. Attached Burn-In Schematic (Spec. # 06-3597) shows the static Burn-In circuit. Maxim also performs quarterly 1000 hour life test monitors. This data is published in the Product Reliability Report (**RR-1M**).

B. Moisture Resistance Tests

Maxim pulls pressure pot samples from every assembly process three times per week. Each lot sample must meet an LTPD = 20 or less before shipment as standard product. Additionally, the industry standard 85°C/85%RH testing is done per generic device/package family once a quarter.

C. E.S.D. and Latch-Up Testing

The OA47 die type has been found to have all pins able to withstand a transient pulse of ± 2000V, per Mil-Std-883 Method 3015 (reference attached ESD Test Circuit). Latch-Up testing has shown that this device withstands a current of ±250mA and/or ±20V.

Table 1
Reliability Evaluation Test Results
MAX412xxxA

TEST ITEM	TEST CONDITION	FAILURE IDENTIFICATION	PACKAGE	SAMPLE SIZE	NUMBER OF FAILURES
Static Life Test (Note 1)					
	Ta = 135°C Biased Time = 192 hrs.	DC Parameters & functionality		80	0
Moisture Testing (Note 2)					
Pressure Pot	Ta = 121°C P = 15 psi. RH= 100% Time = 96hrs.	DC Parameters & functionality	PDIP SO	77 177	0 0
85/85	Ta = 85°C RH = 85% Biased Time = 1000hrs.	DC Parameters & functionality		77	0
Mechanical Stress (Note 2)					
Temperature Cycle	-65°C/150°C 1000 Cycles Method 1010	DC Parameters		77	0

Note 1: Life Test Data may represent plastic D.I.P. qualification lots for the Small Outline package.
Note 2: Generic/Package process data

Attachment #1

TABLE II. Pin combination to be tested. 1/ 2/

	Terminal A (Each pin individually connected to terminal A with the other floating)	Terminal B (The common combination of all like-named pins connected to terminal B)
1.	All pins except V_{PS1} 3/	All V_{PS1} pins
2.	All input and output pins	All other input-output pins

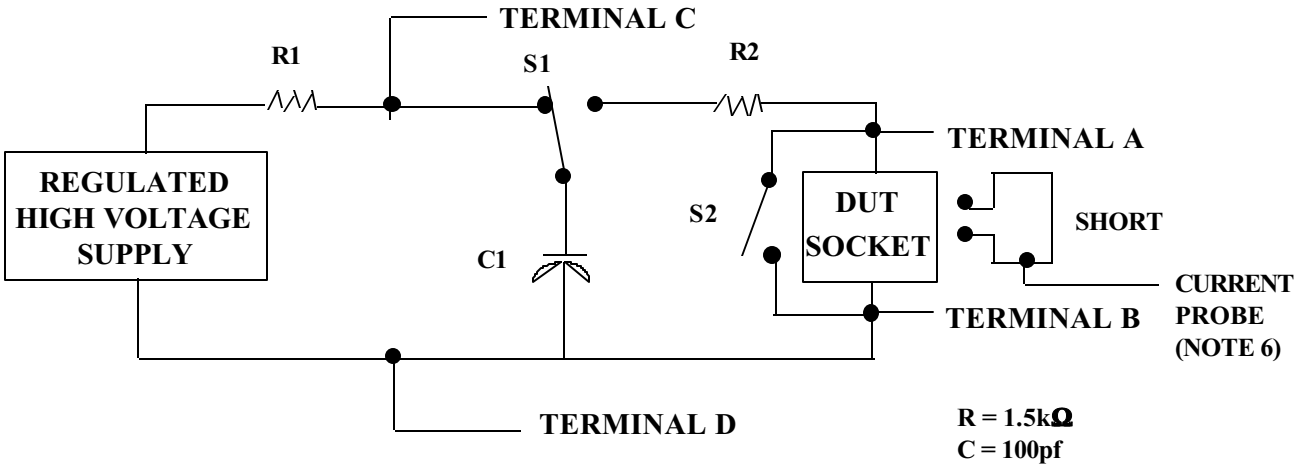
1/ Table II is restated in narrative form in 3.4 below.
2/ No connects are not to be tested.
3/ Repeat pin combination I for each named Power supply and for ground (e.g., where V_{PS1} is V_{DD}, V_{CC}, V_{SS}, V_{BB}, GND, $+V_S$, $-V_S$, V_{REF}, etc).

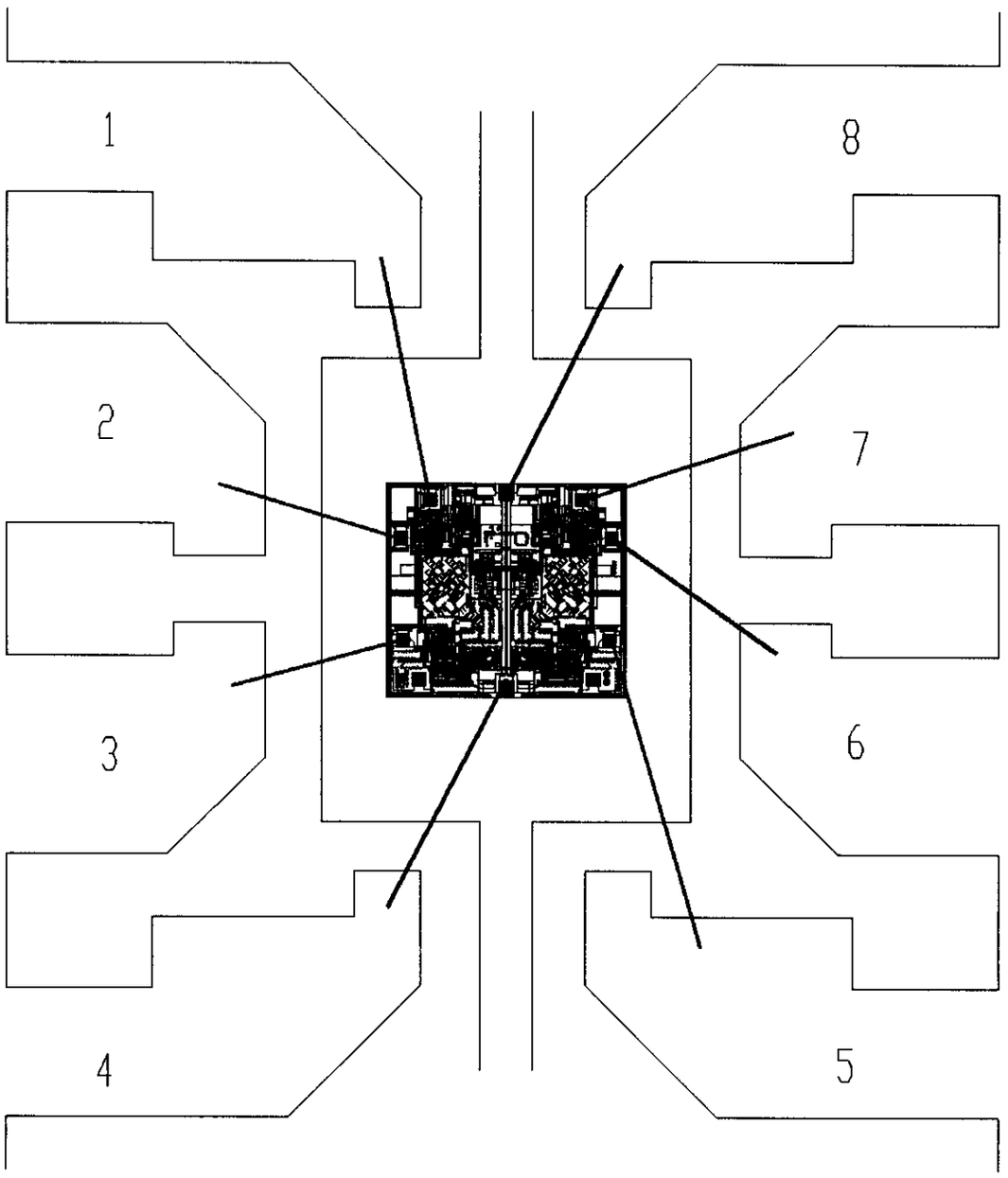
3.4 Pin combinations to be tested.

a. Each pin individually connected to terminal A with respect to the device ground pin(s) connected to terminal B. All pins except the one being tested and the ground pin(s) shall be open.

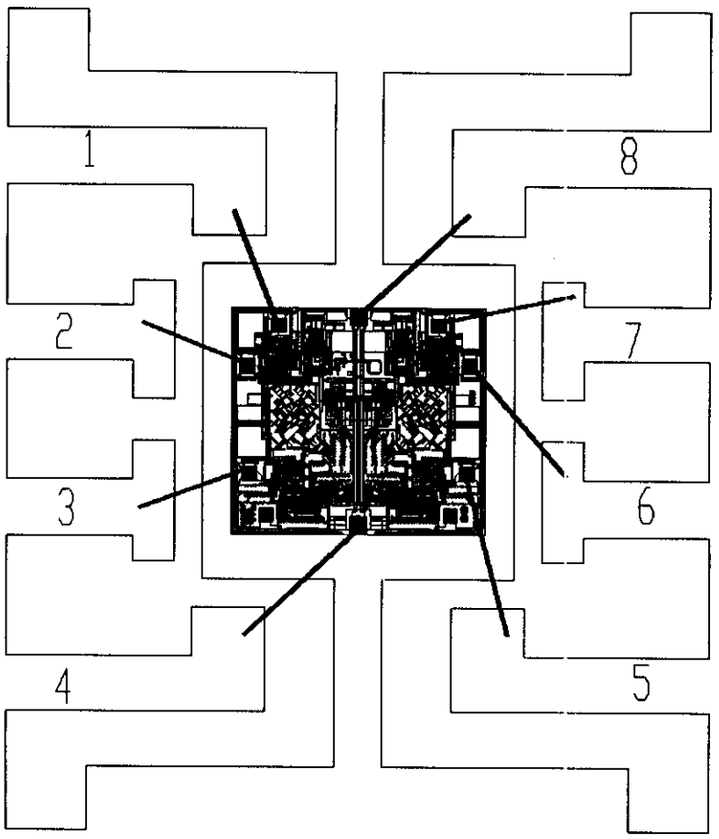
b. Each pin individually connected to terminal A with respect to each different set of a combination of all named power supply pins (e.g., V_{SS1}, or V_{SS2} or V_{SS3} or V_{CC1}, or V_{CC2}) connected to terminal B. All pins except the one being tested and the power supply pin or set of pins shall be open.

c. Each input and each output individually connected to terminal A with respect to a combination of all the other input and output pins connected to terminal B. All pins except the input or output pin being tested and the combination of all the other input and output pins shall be open.

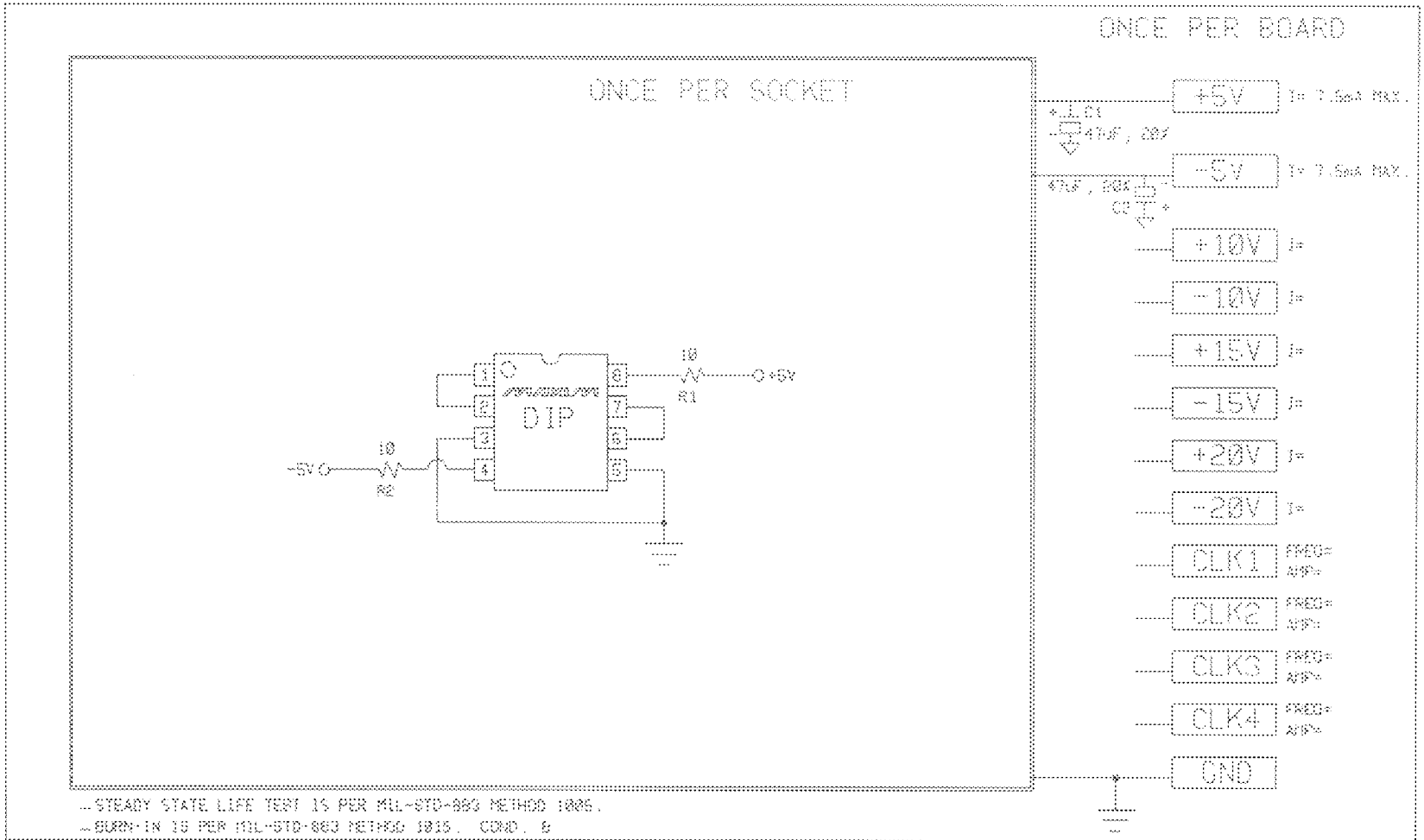




PKG.CODE: P8-2		APPROVALS	DATE	MAXIM	
CAV./PAD SIZE: 110 X 140	PKG.		4/12/92	BUILDSHEET NUMBER:	REV.:
	DESIGN		4/17/92	05-0601-0324	A



PKG.CODE: S8-2		APPROVALS	DATE	MAXIM	
CAV./PAD SIZE: 90 X 90	PKG.		4/16/92	BUILDSHEET NUMBER:	REV.:
	DESIGN		4/17/92	05-0601-0325	A



- STEADY STATE LIFE TEST IS PER MIL-STD-883 METHOD 1005.
- BURN-IN IS PER MIL-STD-883 METHOD 1015, COND. B

NOTES:

1. TEMPERATURE: 125C OR EQUIVALENT
2. TIME: 160 HOURS MIN. OR EQUIVALENT
3. ALL COMPONENTS AND MATERIAL MUST STAND 150C CONTINUOUS
4. APPROVED FOR LOW COMMERCIAL [ ] MIL/883

SPEC. NO. 06-3597 REV. C

DATE: 6/3/92

DRAWN BY: N.K. NGUYEN

MAXIM BURN-IN SCHEMATIC

DEVICE TYPE:

MAX412/4114
MAX463